



Underwriters
Laboratories.

Test report No. : 31AE0134-HO-01-B-R1
Page : 1 of 25
Issued date : September 9, 2010
Revised date : September 27, 2010
FCC ID : E4EV640HAM11L

RADIO TEST REPORT

Test Report No. : 31AE0134-HO-01-B-R1

Applicant : OMRON Corporation

Type of Equipment : Carrier ID Reader/Writer (RFID)

Model No. : V640-HAM11-L-ETN

FCC ID : E4EV640HAM11L

Test regulation : FCC Part 15 Subpart C 2010

Test Result : Complied

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2. The results in this report apply only to the sample tested.
3. This sample tested is in compliance with above regulation.
4. The test results in this report are traceable to the national or international standards.
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6. This report is a revised version of 31AE0134-HO-01-B. 31AE0134-HO-01-B is replaced with this report.

Date of test: August 26 and 27, 2010

**Representative
test engineer:**

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Engineer of EMC Service

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Manager of EMC Service



NVLAP LAB CODE: 200572-0

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<http://www.ul.com/japan/jpn/pages/services/emc/about/mark1/index.jsp#nvlap>

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MF058b (15.09.10)

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SECTION 1: Customer information

Company Name : OMRON Corporation
Address : 2-2-1, Nishikusatsu, Kusatsu-city, Shiga-pref., 525-0035, Japan
Telephone Number : +81-77-565-5287
Facsimile Number : +81-77-565-5569
Contact Person : Kazunori Morikawa

SECTION 2: Equipment under test (E.U.T.)

2.1 Identification of E.U.T.

Type of Equipment : Carrier ID Reader/Writer (RFID)
Model No. : V640-HAM11-L-ETN
Serial No. : Refer to Section 4, Clause 4.2
Rating : DC 24V
Receipt Date of Sample : August 23, 2010
Country of Mass-production : Japan
Condition of EUT : Production prototype
Modification of EUT : No Modification by the test lab

2.2 Product Description

General Specification

Clock frequency(ies) in the system : 17.1776MHz, 8MHz, 50MHz

Radio Specification

Radio Type : Transceiver
Frequency of Operation : 134.2 kHz
Modulation : Amplitude Shift Keying
Power Supply (radio part input) : DC 8V
Antenna type : Loop Coil Antenna

Similar model

This EUT has similar model: V640-HAM11-L.

- V640-HAM11-L-ETN: EtherNet Communication type and Long distance type
- V640-HAM11-L: Serial Communication type and Long distance type

There is no difference except for these.

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SECTION 3: Test specification, procedures & results

3.1 Test Specification

Test Specification : FCC Part15 Subpart C: 2010, final revised on January 22, 2010 and effective March 1, 2010

Title : FCC 47CFR Part15 Radio Frequency Device Subpart C Intentional Radiators
 Section 15.207 Conducted Emission
 Section 15.209 Radiated emission limits, general requirements

FCC 15.31 (e)

This EUT provides stable voltage (DC 8V) constantly to RF part regardless of input voltage. Therefore, this EUT complies with the requirement.

FCC Part 15.203 Antenna requirement

The EUT has an external antenna connector, but it is installed by the professionals. Therefore, the equipment complies with the antenna requirement of Section 15.203.

3.2 Procedures and results

No.	Item	Test Procedure	Specification	Remarks	Deviation	Worst margin	Results
1	Conducted Emission	<FCC> ANSI C63.4:2003 7. AC powerline conducted emission measurements <IC> RSS-Gen 7.2.2	<FCC> Section 15.207 <IC> RSS-Gen 7.2.2	-	N/A	[QP] 25.4dB 0.19263MHz, L [AV] 24.3dB 0.40578MHz, N (With Tag)	Complied
2	Electric Field Strength of Fundamental Emission	<FCC> ANSI C63.4:2003 13. Measurement of intentional radiators <IC> RSS-210 2.6, 2.7	<FCC> Section 15.209 <IC> RSS-210 2.6, 2.7	Radiated	N/A	9.6dB 0.13420MHz 0deg. AV (Without Tag)	Complied
3	Electric Field Strength of Spurious Emission	<FCC> ANSI C63.4:2003 13. Measurement of intentional radiators <IC> RSS-Gen 4.9, 4.11	<FCC> Section 15.209 <IC> RSS-210 2.6, 2.7	Radiated	N/A	0.4dB 61.740MHz Vertical (With Tag/ Without Tag)	Complied
4	-26dB Bandwidth	<FCC> ANSI C63.4:2003 13. Measurement of intentional radiators <IC> -	<FCC> Reference data <IC> -	Radiated	N/A	N/A	N/A

Note: UL Japan, Inc.'s EMI Work Procedures No.QPM05 and QPM15.

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3.3 Addition to standard

No.	Item	Test Procedure	Specification	Remarks	Deviation	Worst margin	Results
1	99% Occupied Band Width	RSS-Gen 4.6.1	RSS-Gen 4.6.1	Radiated	N/A	N/A	N/A

Other than above, no addition, exclusion nor deviation has been made from the standard.

3.4 Uncertainty

EMI

The following uncertainties have been calculated to provide a confidence level of 95% using a coverage factor k=2.

Test room (semi-anechoic chamber)	Conducted emission (\pm dB)	
	150kHz-30MHz	
No.1	2.6dB	
No.2	2.9dB	
No.3	3.3dB	
No.4	2.8dB	

Test room (semi-anechoic chamber)	Radiated emission (10m*)(\pm dB)		
	9kHz -30MHz	30MHz -300MHz	300MHz -1GHz
No.1	2.7dB	4.8dB	5.0dB
No.2	-	-	-
No.3	-	-	-
No.4	-	-	-

*10m = Measurement distance

Test room (semi-anechoic chamber)	Radiated emission						
	(3m*)(\pm dB)			(1m*)(\pm dB)		(0.5m*)(\pm dB)	
	9kHz -30MHz	30MHz -300MHz	300MHz -1GHz	1GHz -10GHz	10GHz -18GHz	18GHz -26.5GHz	26.5GHz -40GHz
No.1	2.9dB	4.8dB	5.0dB	3.9dB	4.3dB	4.5dB	4.3dB
No.2	3.5dB	4.8dB	5.1dB	4.0dB	4.2dB	4.4dB	4.2dB
No.3	3.8dB	4.6dB	4.7dB	4.0dB	4.2dB	4.5dB	4.2dB
No.4	3.5dB	4.4dB	4.9dB	4.0dB	4.2dB	4.6dB	4.2dB

*3m/1m/0.5m = Measurement distance

Conducted emission test

The data listed in this test report has enough margin, more than the site margin.

Radiated emission test (3m)

The data listed in this report meets the limits unless the uncertainty is taken into consideration.

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3.5 Test Location

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	FCC Registration Number	IC Registration Number	Width x Depth x Height (m)	Size of reference ground plane (m) / horizontal conducting plane	Other rooms
No.1 semi-anechoic chamber	313583	2973C-1	19.2 x 11.2 x 7.7m	7.0 x 6.0m	No.1 Power source room
No.2 semi-anechoic chamber	655103	2973C-2	7.5 x 5.8 x 5.2m	4.0 x 4.0m	-
No.3 semi-anechoic chamber	148738	2973C-3	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.3 Preparation room
No.3 shielded room	-	-	4.0 x 6.0 x 2.7m	N/A	-
No.4 semi-anechoic chamber	134570	2973C-4	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.4 Preparation room
No.4 shielded room	-	-	4.0 x 6.0 x 2.7m	N/A	-
No.5 semi-anechoic chamber	-	-	6.0 x 6.0 x 3.9m	6.0 x 6.0m	-
No.6 shielded room	-	-	4.0 x 4.5 x 2.7m	4.75 x 5.4 m	-
No.6 measurement room	-	-	4.75 x 5.4 x 3.0m	4.75 x 4.15 m	-
No.7 shielded room	-	-	4.7 x 7.5 x 2.7m	4.7 x 7.5m	-
No.8 measurement room	-	-	3.1 x 5.0 x 2.7m	N/A	-
No.9 measurement room	-	-	8.0 x 4.5 x 2.8m	2.0 x 2.0m	-
No.10 measurement room	-	-	2.6 x 2.8 x 2.5m	2.4 x 2.4m	-
No.11 measurement room	-	-	3.1 x 3.4 x 3.0m	2.4 x 3.4m	-

* Size of vertical conducting plane (for Conducted Emission test) : 2.0 x 2.0m for No.1, No.2, No.3, and No.4 semi-anechoic chambers and No.3 and No.4 shielded rooms.

3.6 Test set up, Data of EMI, and Test instruments

Refer to APPENDIX.

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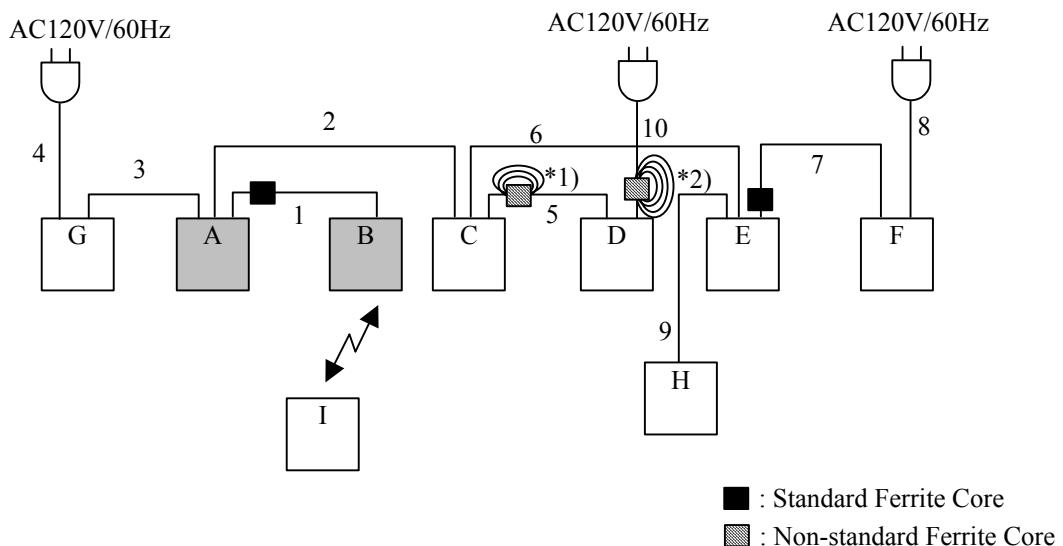
SECTION 4: Operation of E.U.T. during testing

4.1 Operating Modes

Test mode	Remarks
Communication 134.2kHz With Tag mode	-
Communication 134.2kHz Without Tag mode	
Software: V640 demo soft, Version: 1.0.0.0 This software does not have a Power Control function. The test was performed with Default value written on RF module ROM. Mass-produced product will have same level as it.	

Justification : The system was configured in typical fashion (as a customer would normally use it) for testing.

4.2 Configuration and peripherals



* Cabling and setup were taken into consideration and test data was taken under worse case conditions.

Description of EUT and Support equipment

No.	Item	Model number	Serial number	Manufacturer	Remarks
A	Carrier ID Reader/Writer (Amplifier Unit)	V640-HAM11-L-ETN	9	OMRON Corporation	EUT
B	Antenna (CIDRW Head)	V640-HS62	8	OMRON Corporation	EUT
C	Switching HUB	W4S1-05B	17310K	OMRON Corporation	-
D	DC Power Supply	S8VS-03024	08480M	OMRON Corporation	-
E	Laptop PC	13N5432	11S13N5432Z1Z90 V47L02P	IBM	-
F	AC Adapter	02K6808	11S02K6808Z1Z89 H3C9TH0	IBM	-
G	DC Power Supply	S82K-01524	21	OMRON Corporation	-
H	Mouse	M-UB48	830318-0000	Logitech	-
I	Tag	RI-TRP-DR2B	100	Texas Instruments	-

List of cables used

No.	Name	Length (m)	Shield		Remark
			Cable	Connector	
1	Antenna Cable	2.0	Shielded	Shielded	-
2	LAN Cable	5.0	Shielded	Shielded	-
3	DC Cable	0.6	Unshielded	Unshielded	-
4	AC Cable	1.9	Unshielded	Unshielded	-
5	DC Cable	0.15	Unshielded	Unshielded	*1)
6	LAN Cable	5.0	Shielded	Shielded	-
7	DC Cable	1.8	Unshielded	Unshielded	-
8	AC Cable	1.0	Unshielded	Unshielded	-
9	Mouse Cable	0.8	Unshielded	Unshielded	-
10	AC Cable	1.4	Unshielded	Unshielded	*2)

<Notes for Ferrite cores>

*1) Model No. ZCAT2032-0930 (Manufacturer: TDK-EPC), 3cm from Item C, 4turn

*2) Model No. ZCAT3035-1330 (Manufacturer: TDK-EPC), 11cm from Item D, 5turn

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SECTION 5: Conducted Emission

Test Procedure and conditions

EUT was placed on a urethane platform of nominal size, 1.0m by 1.5m, raised 0.8m above the conducting ground plane. The rear of tabletop was located 40cm to the vertical conducting plane. The rear of EUT, including peripherals aligned and flushed with rear of tabletop. All other surfaces of tabletop were at least 80cm from any other grounded conducting surface. EUT was located 80cm from a Line Impedance Stabilization Network (LISN)/ Artificial mains Network (AMN) and excess AC cable was bundled in center.

For the tests on EUT itself (as a stand alone equipment)

Each EUT current-carrying power lead, except the ground (safety) lead, was individually connected through a LISN / (AMN) to the input power source. All unused 50ohm connectors of the LISN(AMN) were resistivity terminated in 50ohm when not connected to the measuring equipment.

The AC Mains Terminal Continuous disturbance Voltage has been measured with the EUT in a Semi Anechoic Chamber or a Measurement Room.

The EUT was connected to a LISN (AMN).

An overview sweep with peak detection has been performed.

Detector	: CISPR quasi-peak and average detector (IF BW 9 kHz)
Measurement range	: 0.15-30MHz
Test data	: APPENDIX 2
Test result	: Pass

Date: August 27, 2010

Test engineer: Hisayoshi Sato

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SECTION 6: Radiated emission (Fundamental and Spurious Emission)

Test Procedure

The Radiated Electric Field Strength intensity has been measured on No 4 semi anechoic chamber with a ground plane and at a distance of 3m.

Frequency : From 9kHz to 30MHz at distance 3m

The EUT was rotated a full revolution in order to obtain the maximum value of the electric field intensity.

The measurements were performed for vertical polarization (antenna angle: 0deg., 45deg., 90deg., and 135 deg.) and horizontal polarization.

*Refer to Figure 1 about Direction of the Loop Antenna.

Frequency : From 30MHz to 1GHz at distance 3m

The measuring antenna height varied between 1 and 4m and EUT was rotated a full revolution in order to obtain the maximum value of the electric field intensity.

The measurements were performed for both vertical and horizontal antenna polarization.

Measurements were performed with a QP, PK, and AV detector.

The radiated emission measurements were made with the following detector function of the test receiver.

	From 9kHz to 90kHz and From 110kHz to 150kHz	From 90kHz to 110kHz	From 150kHz to 490kHz	From 490kHz to 30MHz	From 30MHz to 1GHz
Detector Type	PK/AV	QP	PK/AV	QP	QP
IF Bandwidth	200Hz	200Hz	9kHz	9kHz	120kHz

- The carrier level (or, noise levels) was (or were) measured at each position of all three axes X, Y and Z, and the position that has the maximum noise was determined.

With the position, the noise levels of all the frequencies were measured.

* Part 15 Section 15.31 (f)(2) (9kHz-30MHz)
 [Limit at 3m]=[Limit at 300m]-40 x log (3[m]/300[m])
 [Limit at 3m]=[Limit at 30m]-40 x log (3[m]/30[m])

Test data : APPENDIX 2
Test result : Pass

Date: August 26, 2010

Test engineer: Hisayoshi Sato and Satofumi Matsuyama

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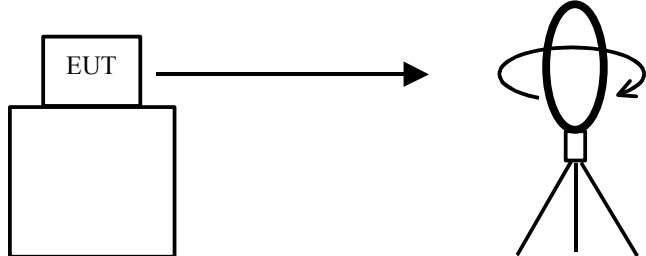
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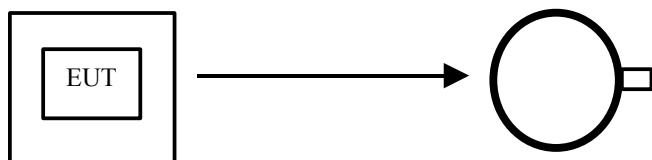
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Figure 1: Direction of the Loop Antenna

Side View (Vertical)

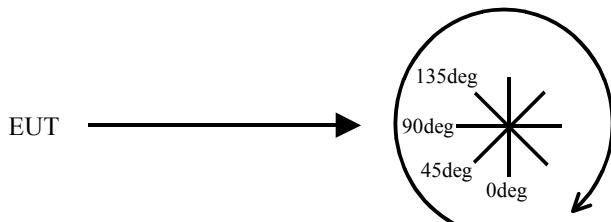


Top View (Horizontal)



Antenna was not rotated.

Top View (Vertical)



Front side: 0 deg.
Forward direction: clockwise

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SECTION 7: -26dB Bandwidth

Test Procedure

The measurement was performed in the antenna height to gain the maximum of Electric field strength.

Test	Span	RBW	VBW	Sweep	Detector	Trace	Instrument used
-26dB Bandwidth	100kHz	1kHz	3kHz	Auto	Peak	Max Hold	Spectrum Analyzer

Test data : APPENDIX 2
Test result : Pass

SECTION 8: 99% Occupied Bandwidth

Test Procedure

The measurement was performed in the antenna height to gain the maximum of Electric field strength.

Test	Span	RBW	VBW	Sweep	Detector	Trace	Instrument used
99% Occupied Bandwidth	Enough width to display 20dB Bandwidth	1 % of Span	Three times of RBW	Auto	Peak *1)	Max Hold *1)	Spectrum Analyzer

*1) The measurement was performed with Peak detector, Max Hold since the duty cycle was not 100%.

Test data : APPENDIX 2
Test result : Pass

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